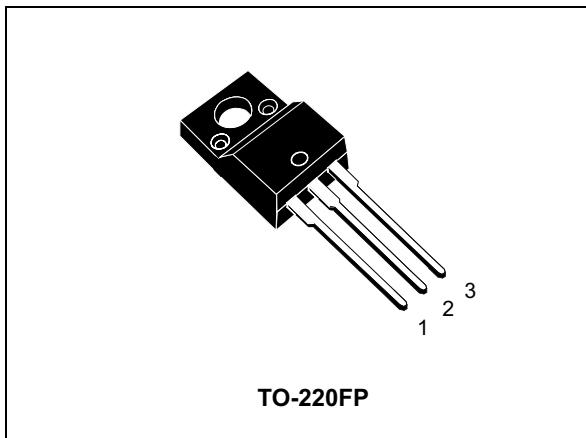
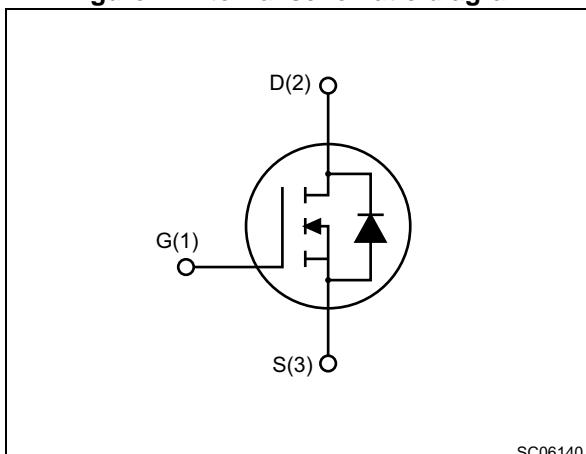


## N-channel 500 V, 0.40 $\Omega$ typ., 8.5 A MDmesh™ II Power MOSFET in a TO-220FP package

Datasheet - production data



**Figure 1. Internal schematic diagram**



### Features

| Order code | $V_{DS} @ T_J \max$ | $R_{DS(on)} \max$ | $I_D$ |
|------------|---------------------|-------------------|-------|
| STF11NM50N | 550 V               | 0.47 $\Omega$     | 8.5 A |

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

### Applications

- Switching applications

### Description

This device is an N-channel Power MOSFET developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

**Table 1. Device summary**

| Order code | Marking | Package  | Packaging |
|------------|---------|----------|-----------|
| STF11NM50N | 11NM50N | TO-220FP | Tube      |

## Contents

|          |                                     |           |
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# 1 Electrical ratings

Table 2. Absolute maximum ratings

| Symbol         | Parameter   | Value              | Unit             |
|----------------|---|--------------------|------------------|
| $V_{DS}$       | Drain-source voltage  | 500                | V                |
| $V_{GS}$       | Gate-source voltage   | $\pm 25$           | V                |
| $I_D$          | Drain current (continuous) at $T_C = 25^\circ\text{C}$  | 8.5 <sup>(1)</sup> | A                |
| $I_D$          | Drain current (continuous) at $T_C = 100^\circ\text{C}$   | 6 <sup>(1)</sup>   | A                |
| $I_{DM}^{(2)}$ | Drain current (pulsed)  | 34 <sup>(1)</sup>  | A                |
| $P_{TOT}$      | Total dissipation at $T_C = 25^\circ\text{C}$   | 25                 | W                |
| $dv/dt^{(3)}$  | Peak diode recovery voltage slope   | 15                 | V/ns             |
| $V_{ISO}$      | Insulation withstand voltage (RMS) from all three leads to external heat sink ( $t = 1 \text{ s}; T_C = 25^\circ\text{C}$ ) | 2500               | V                |
| $T_{stg}$      | Storage temperature   | - 55 to 150        | $^\circ\text{C}$ |
| $T_j$          | Max. operating junction temperature   | 150                | $^\circ\text{C}$ |

1. Limited by maximum junction temperature
2. Pulse width limited by safe operating area.
3.  $I_{SD} \leq 8.5 \text{ A}$ ,  $di/dt \leq 400 \text{ A}/\mu\text{s}$ ,  $V_{DSpeak} \leq V_{(BR)DSS}$ ,  $V_{DD} = 80\% V_{(BR)DSS}$

Table 3. Thermal data

| Symbol         | Parameter                               | Value | Unit                      |
|----------------|---|-------|---------------------------|
| $R_{thj-case}$ | Thermal resistance junction-case max    | 5     | $^\circ\text{C}/\text{W}$ |
| $R_{thj-amb}$  | Thermal resistance junction-ambient max | 62.5  | $^\circ\text{C}/\text{W}$ |

Table 4. Avalanche characteristics

| Symbol   | Parameter   | Value | Unit |
|----------|---|-------|------|
| $I_{AR}$ | Avalanche current, repetitive or not-repetitive (pulse width limited by $T_{j\max}$ )                   | 3     | A    |
| $E_{AS}$ | Single pulse avalanche energy (starting $T_j=25^\circ\text{C}$ , $I_D=I_{AR}$ , $V_{DD}=50 \text{ V}$ ) | 150   | mJ   |

## 2 Electrical characteristics

( $T_{CASE} = 25^\circ\text{C}$  unless otherwise specified)

**Table 5. On/off states**

| Symbol        | Parameter  | Test conditions   | Min. | Typ. | Max.      | Unit                           |
|---------------|--|---|------|------|-----------|--------------------------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage                   | $I_D = 1 \text{ mA}, V_{GS} = 0$  | 500  |      |           | V                              |
| $I_{DSS}$     | Zero gate voltage drain current ( $V_{GS} = 0$ ) | $V_{DS} = 500 \text{ V}$<br>$V_{DS} = 500 \text{ V}, T_C = 125^\circ\text{C}$ |      |      | 1<br>100  | $\mu\text{A}$<br>$\mu\text{A}$ |
| $I_{GSS}$     | Gate-body leakage current ( $V_{DS} = 0$ )       | $V_{GS} = \pm 25 \text{ V}$   |      |      | $\pm 100$ | $\mu\text{A}$                  |
| $V_{GS(th)}$  | Gate threshold voltage                           | $V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$                                      | 2    | 3    | 4         | V                              |
| $R_{DS(on)}$  | Static drain-source on-resistance                | $V_{GS} = 10 \text{ V}, I_D = 4.5 \text{ A}$                                  |      | 0.40 | 0.47      | $\Omega$                       |

**Table 6. Dynamic**

| Symbol            | Parameter                     | Test conditions   | Min. | Typ. | Max. | Unit     |
|-------------------|-------------------------------|---|------|------|------|----------|
| $C_{iss}$         | Input capacitance             |   | -    | 547  | -    | pF       |
| $C_{oss}$         | Output capacitance            | $V_{DS} = 50 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0$  | -    | 42   | -    | pF       |
| $C_{rss}$         | Reverse transfer capacitance  |   | -    | 2    | -    | pF       |
| $C_{oss eq. (1)}$ | Equivalent output capacitance | $V_{GS} = 0, V_{DS} = 0 \text{ to } 400 \text{ V}$  | -    | 210  | -    | pF       |
| $Q_g$             | Total gate charge             |   | -    | 19   | -    | nC       |
| $Q_{gs}$          | Gate-source charge            | $V_{DD} = 400 \text{ V}, I_D = 8.5 \text{ A}, V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 14</a> ) | -    | 3.7  | -    | nC       |
| $Q_{gd}$          | Gate-drain charge             |   | -    | 10   | -    | nC       |
| $R_G$             | Gate input resistance         | $f=1 \text{ MHz}, I_D=0$  | -    | 5.8  | -    | $\Omega$ |

1.  $C_{oss eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DS}$

**Table 7. Switching times**

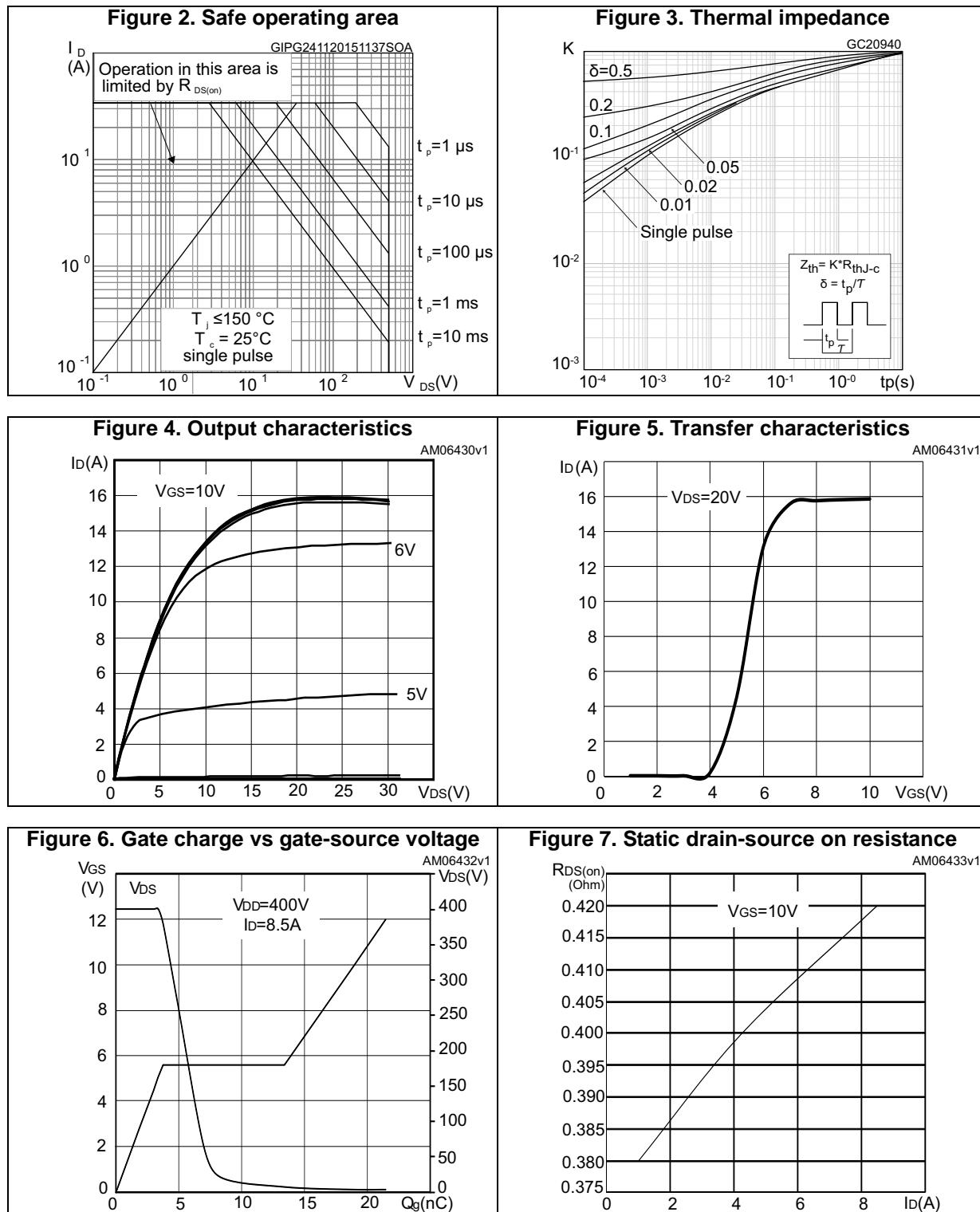
| Symbol       | Parameter           | Test conditions  | Min. | Typ. | Max. | Unit |
|--------------|---------------------|--|------|------|------|------|
| $t_{d(on)}$  | Turn-on delay time  | $V_{DD} = 250 \text{ V}$ , $I_D = 4.25 \text{ A}$<br>$R_G = 4.7 \Omega$ $V_{GS} = 10 \text{ V}$<br>(see <a href="#">Figure 15</a> and<br><a href="#">Figure 18</a> ) | -    | 8    | -    | ns   |
| $t_r$        | Rise time           |  | -    | 10   | -    | ns   |
| $t_{d(off)}$ | Turn-off delay time |  | -    | 33   | -    | ns   |
| $t_f$        | Fall time           |  | -    | 10   | -    | ns   |

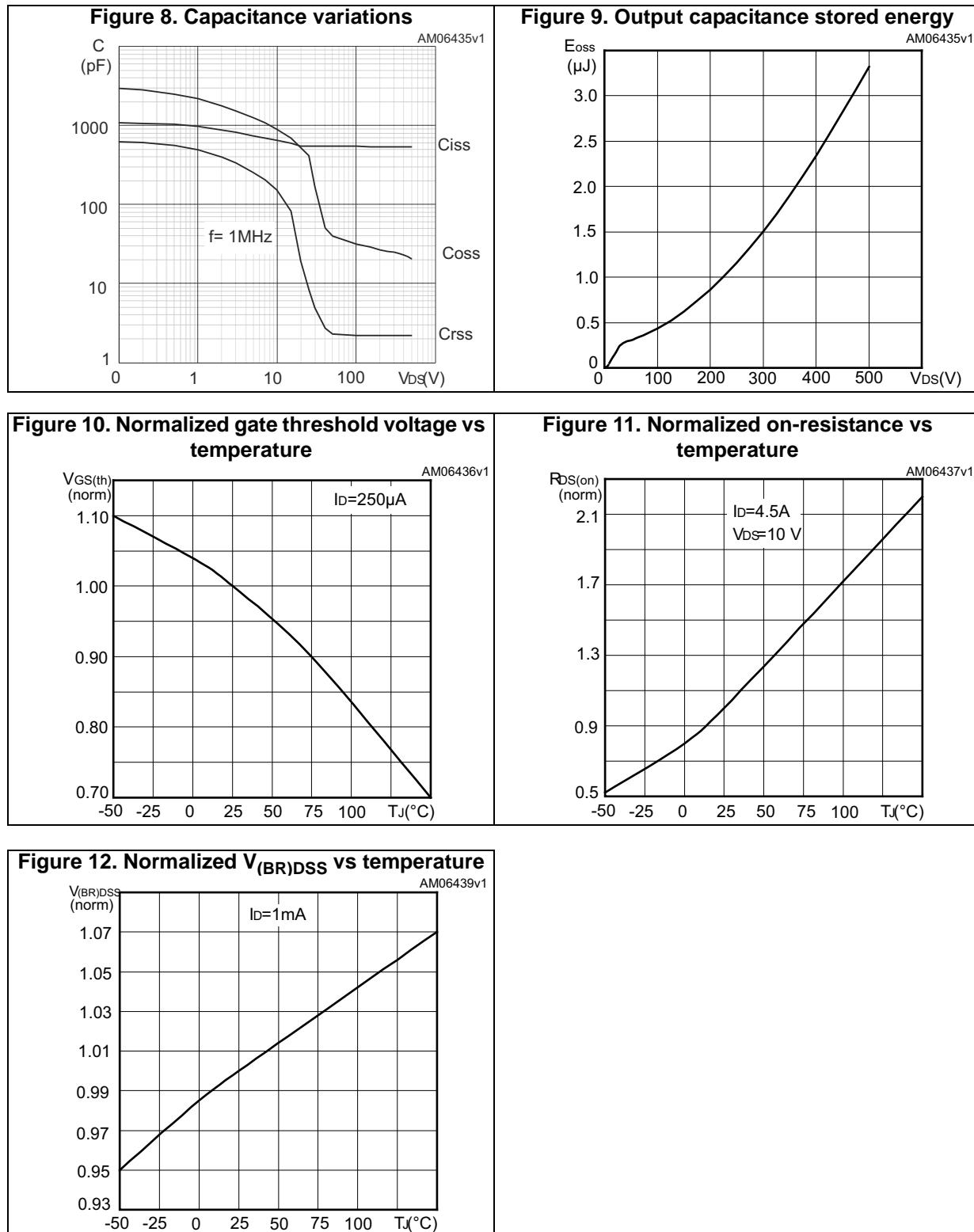
**Table 8. Source drain diode**

| Symbol                      | Parameter                     | Test conditions  | Min. | Typ. | Max. | Unit          |
|-----------------------------|-------------------------------|--|------|------|------|---------------|
| $I_{SD}$<br>$I_{SDM}^{(1)}$ | Source-drain current          |  | -    |      | 8.5  | A             |
|                             | Source-drain current (pulsed) |  |      |      | 34   | A             |
| $V_{SD}^{(2)}$              | Forward on voltage            | $I_{SD} = 8.5 \text{ A}$ , $V_{GS} = 0$                            | -    |      | 1.5  | V             |
|                             | Reverse recovery time         |  | -    | 230  |      | ns            |
| $Q_{rr}$                    | Reverse recovery charge       | $I_{SD} = 8.5 \text{ A}$ , $dI/dt = 100$<br>$\text{A}/\mu\text{s}$ | -    | 2.1  |      | $\mu\text{C}$ |
|                             | Reverse recovery current      |  | -    | 18   |      | A             |
| $t_{rr}$                    | Reverse recovery time         | $I_{SD} = 8.5 \text{ A}$ , $dI/dt = 100$<br>$\text{A}/\mu\text{s}$ | -    | 275  |      | ns            |
|                             | Reverse recovery charge       |  | -    | 2.5  |      | $\mu\text{C}$ |
| $I_{RRM}$                   | Reverse recovery current      | $V_{DD} = 60 \text{ V}$ (see <a href="#">Figure 15</a> )           | -    | 18   |      | A             |

1. Pulse width limited by safe operating area.
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

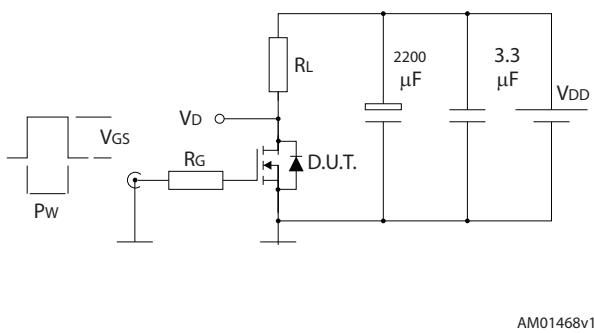
## 2.1 Electrical characteristics (curves)



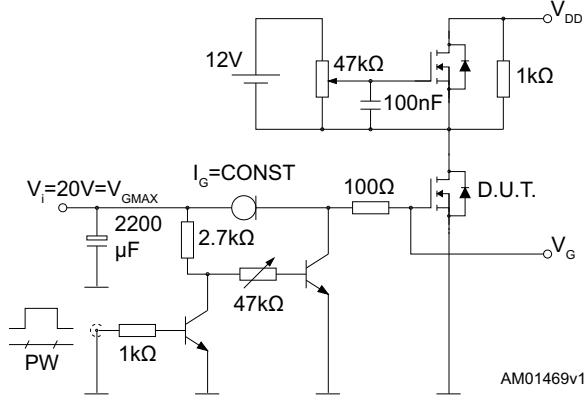


## 3 Test circuits

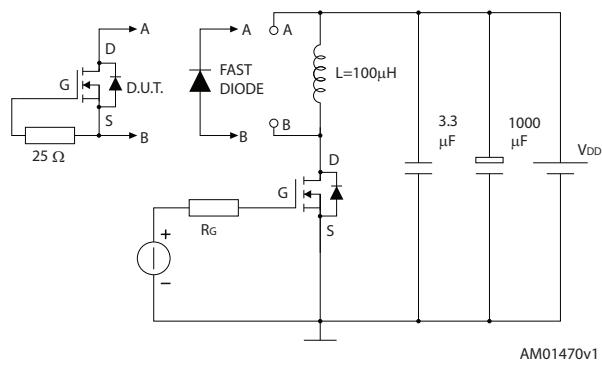
**Figure 13. Test circuit for resistive load switching times**



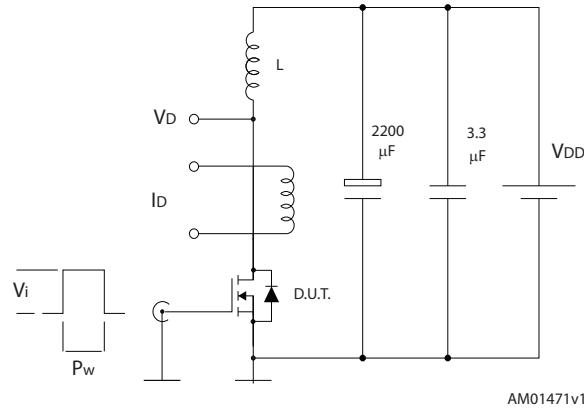
**Figure 14. Test circuit for gate charge behavior**



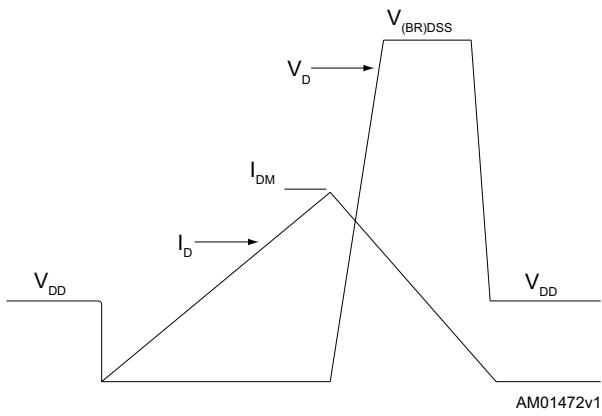
**Figure 15. Test circuit for inductive load switching and diode recovery times**



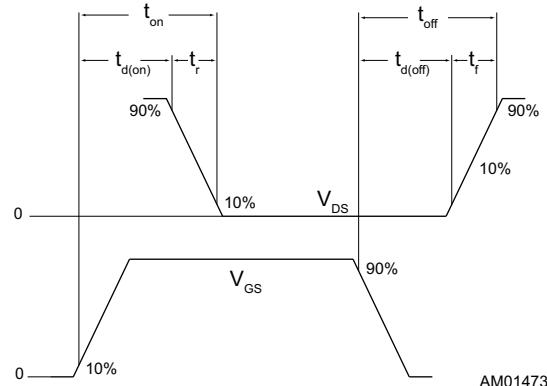
**Figure 16. Unclamped inductive load test circuit**



**Figure 17. Unclamped inductive waveform**



**Figure 18. Switching time waveform**

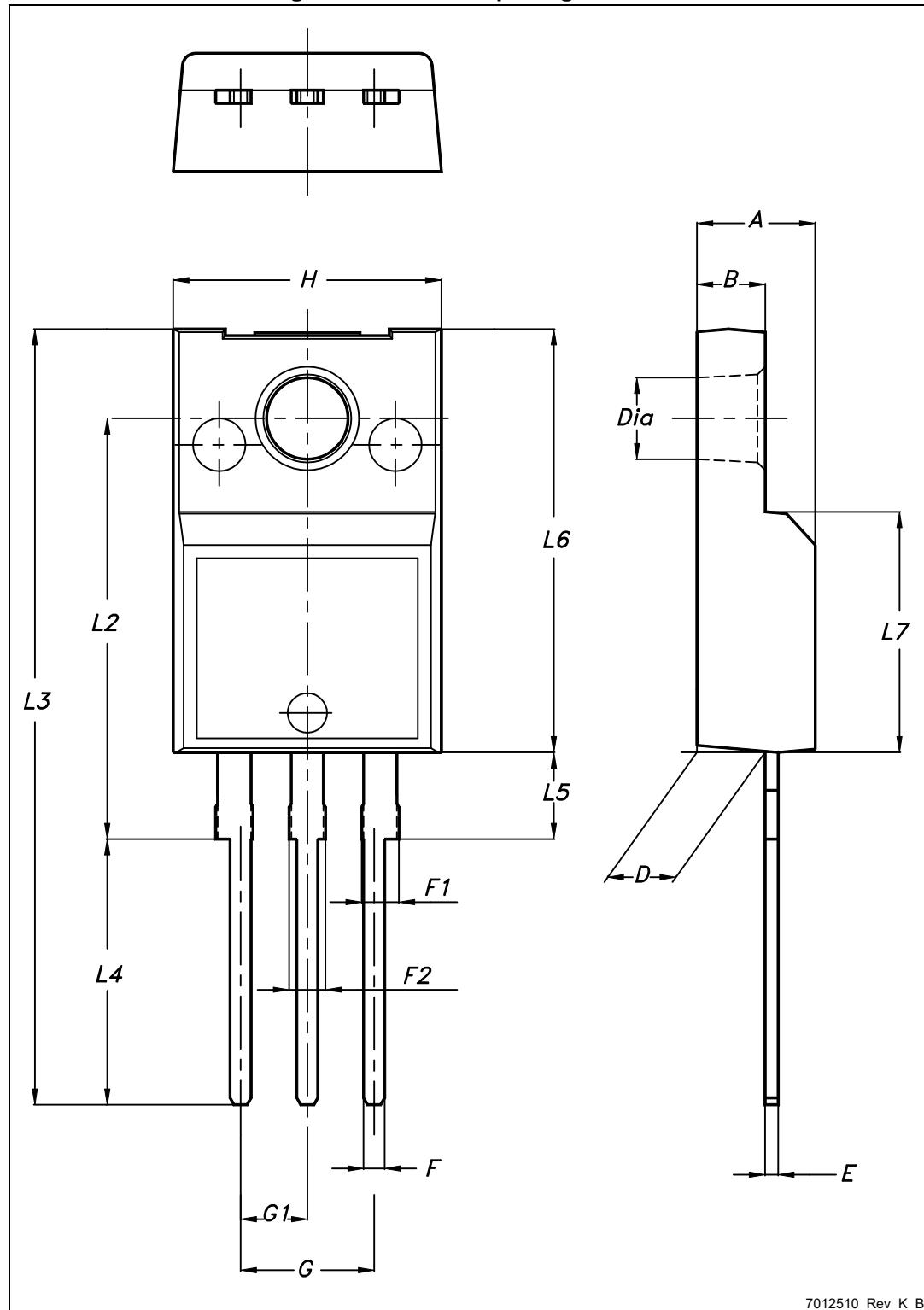


## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK is an ST trademark.

## 4.1 TO-220FP package information

Figure 19. TO-220FP package outline



**Table 9. TO-220FP mechanical data**

| Dim. | mm   |      |      |
|------|------|------|------|
|      | Min. | Typ. | Max. |
| A    | 4.4  |      | 4.6  |
| B    | 2.5  |      | 2.7  |
| D    | 2.5  |      | 2.75 |
| E    | 0.45 |      | 0.7  |
| F    | 0.75 |      | 1    |
| F1   | 1.15 |      | 1.70 |
| F2   | 1.15 |      | 1.70 |
| G    | 4.95 |      | 5.2  |
| G1   | 2.4  |      | 2.7  |
| H    | 10   |      | 10.4 |
| L2   |      | 16   |      |
| L3   | 28.6 |      | 30.6 |
| L4   | 9.8  |      | 10.6 |
| L5   | 2.9  |      | 3.6  |
| L6   | 15.9 |      | 16.4 |
| L7   | 9    |      | 9.3  |
| Dia  | 3    |      | 3.2  |

## 5 Revision history

**Table 10. Document revision history**

| Date        | Revision | Changes   |
|-------------|----------|---|
| 25-Nov-2015 | 1        | First release. Part number previously included in datasheet<br>DocID17156 |

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